

Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 05770-097001	Application No. 09/615,999
<b>Information Disclosure Statement by Applicant</b> (Use several sheets if necessary) (37 CFR §1.98(b))		Applicant Wei Zhang et al.	
		Filing Date July 14, 2000	Group Art Unit

## U.S. Patent Documents

Examiner Initial	Desig. ID	Patent Number	Issue Date	Patentee	Class	Subclass	Filing Date If Appropriate
BT	AA	3,763,552	10/09/73	Brown et al.			
	AB	3,985,281	10/12/76	Diepers et al.			
	AC	4,442,396	04/10/84	Hucker			
	AD	4,659,973	04/21/87	Stich			
	AE	4,994,433	02/19/91	Chiang			
	AF	5,038,127	08/06/91	Dersch			
	AG	5,071,828	12/10/91	Greuter et al.			
	AH	5,073,537	12/17/91	Hung et al.			
	AI	5,449,659	09/12/95	Garrison et al.			
	AJ	5,866,252	02/02/99	de Rochemont et al.			
BT	AK	5,968,877	10/19/99	Budai et al.			

## Foreign Patent Documents or Published Foreign Patent Applications

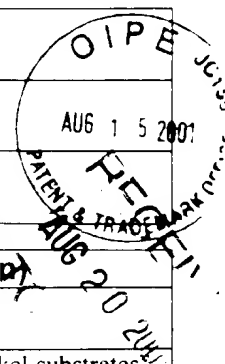
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
BT	AL	0 387 525	09/19/90	Europe				
	AM	0 431 782	06/12/91	Europe				
	AN	0 584 410	03/02/94	Europe				
	AO	0 872 579	10/21/98	Europe				
	AP	57075564	05/12/82	Japan (Abstract Only)			X	
	AQ	63310366	12/19/88	Japan (Abstract Only)			X	
	AR	WO 97/05669	02/13/97	WIPO				
BT	AS	WO 99/35083	07/15/99	WIPO				

## Other Documents (include Author, Title, Date, and Place of Publication)

Examiner Initial	Desig. ID	Document
BT	AT	Apicella, M.L. et al., "The Effects of Surface Contamination on the Biaxially Textured Substrate for YBCO Thick Film Deposition", <i>International Journal of Modern Physics B</i> , Vol. 13, Nos. 9&10 (1999) 997-1004

Examiner Signature B. Talbot	Date Considered 1/16/02
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant	

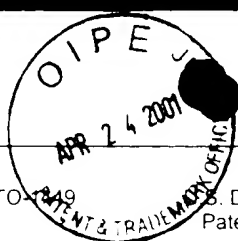
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**Other Documents (include Author, Title, Date, and Place of Publication)**

Examiner Initial	Desig. ID	Document
DT	AU	Boffa V. et al., "Laser-ablation deposition of CeO <sub>2</sub> thin films on biaxially textured nickel substrates", <i>Physica C</i> , Vol. 312, (1999), pp. 202-212
	AV	IBM Technical Disclosure Bulletin, "Fabrication of High Temperature Superconducting Films Using Perfluoro-Organometallic Precursors", Vol. 32, No. 5B, October 1989, p. 241
	AW	McIntyre, Paul C. et al., "Effect of growth conditions on the properties and morphology of chemically derived epitaxial thin films of Ba <sub>2</sub> YCu <sub>3</sub> O <sub>x</sub> on (001) LaAlO <sub>3</sub> ", <i>J. Appl. Phys.</i> , Vol. 71, No. 4, February 15, 1992, pp. 1868-1877
	AX	Qing He, D.K. et al., "Deposition of biaxially-oriented metal and oxide buffer-layer films on textured Ni tapes: new substrates for high-current, high-temperature superconductors", <i>Physica C</i> , Vol. 275 (1997) pp. 155-161
BT	AY	Sheth, Atul et al., "Bench Scale Evaluation of Batch Mode Dip-Coating of Sol-Gel LaAlO <sub>3</sub> Buffer Material", <i>IEEE Transactions on Applied Superconductivity</i> , Vol. 9, No. 2, June 1999, pp. 1514-1518

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Examiner Signature B. T. G. 14.5	Date Considered 11/16/02
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		Applicant Wei Zhang, Martin W. Rupich, Suresh Annavarapu, Leslie G. Fritzemeier, Edward J. Siegal, Valery Prunier	
		Filing Date July 14, 2000	Group Art Unit

**Information Disclosure Statement  
by Applicant**

(Use several sheets if necessary)

(37 CFR §1.98(b))

**U.S. Patent Documents**

Examiner Initial	Desig. ID	Patent Number	Issue Date	Patentee	Class	Subclass	Filing Date If Appropriate
BT	AA	5,741,377	4 21 1998	Goyal et al.			

**Foreign Patent Documents or Published Foreign Patent Applications**

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
BT	AB	WO 91 16149	10 31 91	PCT				
	AC							
	AD							
	AE							
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**Other Documents (include Author, Title, Date, and Place of Publication)**

Examiner Initial	Desig. ID	Document
BT	AG	Boffa et al., "Laser-ablation deposition of CeO <sub>2</sub> thin films on biaxially textured nickel substrates", Physica. C 312, 1999, 202-212
BT	AH	Gupta et al., "Superconducting oxide films with high transition temperature prepared from metal trifluoroacetate precursors", 320 Applied Physics Letters 52 1988 13 June No. 24 pp. 2077-2079
BT	AI	McIntyre et al., "Epitaxial nucleation and growth of chemically derived Ba <sub>2</sub> Ycu <sub>3</sub> O <sub>7-x</sub> thin films on (001) SrTiO <sub>3</sub> ", Journal of Applied Physics 77 (1995) 15 May, No. 10
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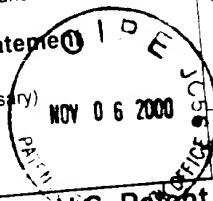
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(37 CFR §1.98(b))



Attorney's Docket No.  
05770-097001

Application No.  
09/615,999

Applicant  
Wei Zhang, Martin W. Rupich, Suresh  
Annavarapu, Leslie G. Fritzemeier, Edward J.  
Siegal, Valery Prunier

Filing Date  
July 14, 2000

Group Art Unit

**U.S. Patent Documents**

Examiner Initial	Desig. ID	Patent Number	Issue Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	5,231,074	07-27-93	Cima et al.			
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**Foreign Patent Documents or Published Foreign Patent Applications**

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AL	WO 98/58415	12-23-93					
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	AO							
	AP							

**Other Documents (include Author, Title, Date, and Place of Publication)**

Examiner Initial	Desig. ID	Document
	AQ	Smith, J.A. et al., "High Critical Current Density Thick MOD-Derived YBCO Films," Transactions on Applied Superconductivity, Vol. 9, No. 2, June 1999
	AR	
	AS	
	AT	

Examiner Signature  
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**U.S. Patent Documents**

Examiner Initial	Desig. ID	Patent Number	Issue Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	6,022,832	02/08/00	Fritzemeier et al.			
	AB	6,172,009	01/09/01	Smith et al.			
	AC	6,256,521	07/03/01	Lee et al.			
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	AI						
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	AQ	
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U.S. Patent Documents							
Examiner Initial	Desig. ID	Patent Number	Issue Date	Patentee	Class	Subclass	Filing Date If Appropriate
BT	AA	6,027,564	02/22/2000	Fritzemeier et al.			
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	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
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Foreign Patent Documents or Published Foreign Patent Applications								
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
BT	AL	WO 99/25908	05/27/99					
I	AM	WO 99/17307	04/08/99					
BT	AN	WO 99/16941	04/08/99					
	AO							
	AP							

Other Documents (include Author, Title, Date, and Place of Publication)		
Examiner Initial	Desig. ID	Document
BT	AQ	Beach et al., "Sol-Gel Synthesis of Rare Earth Aluminate Films as Buffer Layers for High Te Superconducting Films," Mat. Res. Soc. Symp. Proc., vol. 495, 263 (1997)
I	AR	Lee et al., "Alternative Buffer Architectures for High Critical Current Density YBCO Superconducting Deposits on Rolling Assisted Biaxially-Textured Substrates," Japanese J. Appl. Phys., vol. 38, L178 (1999)
BT	AS	Paranthaman et al., "Growth of Biaxially Textured RE <sub>2</sub> O <sub>3</sub> Buffer Layers on Rolled-Ni Substrates Using Reactive Evaporation for HTS-Coated Conductors," Superconductor Sci. Tech., vol. 12, 319 (1999)

Examiner Signature S. J. B. / BT	Date Considered 1/16/02
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**Other Documents (include Author, Title, Date, and Place of Publication)**

Examiner Initial	Desig. ID	Document
BT	AT	Rupich et al., "Growth and Characterization of Oxide Buffer Layers for YBCO Coated Conductors," IEEE Trans. on Appl. Superconductivity, vol. 9 (1999)
I	AU	Shoup et al., "Epitaxial Thin Film Growth of Lanthanum and Neodymium Aluminate Films on Roll-Textured Nickel Using a Sol-Gel Method," J. Am. Cer. Soc., vol. 81, 3019 (1998)
BT	AV	"Silicon Processing for the VLSI Era," vol. 1, eds. S. Wolf and R.N. Tanber, Lattice Press, Sunset Park, CA, pp. 539-574 (1986)

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Patent and Trademark OfficeAttorney's Docket No  
05770-097001Application No  
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35 CFR §1.98(b)

Applicant

Wei Zhang, Martin W. Rupich, Suresh  
Annarapu, Leslie G. Fritzemeier, Edward J.  
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**U.S. Patent Documents**

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Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
BT	AL	0308869	20.09.88	Europe	<del>X</del>	<del>X</del>		
	AM	WO92/05591	02.04.92	PCT				
BT	AN	0506582A2	30.09.92	Europe				
	AO							
	AP							

**Other Documents (include Author, Title, Date, and Place of Publication)**

Examiner Initial	Desig. ID	Document
BT	AQ	He et al., "Growth of Biaxially Oriented Conductive LaNiO <sub>3</sub> Buffer Layers on Textured Ni Tapes for High-T <sub>c</sub> -Coated Conductors," <i>Physica C</i> 314 (1999) p. 105-111
	AR	Koster et al., "Influence of the Surface Treatment on the Homoepitaxial Growth of SrTiO <sub>3</sub> ," <i>Materials Science &amp; Engineering B56</i> (1998) p. 209-212
	AS	Tanaka et al., "Improvement of YBa <sub>2</sub> Cu <sub>3</sub> O <sub>x</sub> Single-Crystal Surface by Chemical Etching," <i>Jpn. J. Appl. Phys. Vol. 38</i> (1999) p. L731-L733
BT	AT	International Search Report

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B. D. B. T.

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11/16/00

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